

IEEE Recommended Practice— Adoption of IEC 61000-4-15:2010, Electromagnetic compatibility (EMC)—Testing and measurement techniques—Flickermeter— Functional and design specifications

IEEE Power & Energy Society

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**IEEE Recommended Practice—
Adoption of IEC 61000-4-15:2010,
Electromagnetic compatibility
(EMC)—Testing and measurement
techniques—Flickermeter—
Functional and design specifications**

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Abstract: IEC 61000-4-15:2010 is adopted by this standard. IEC 61000-4-15:2010 gives a functional and design specification for flicker measuring apparatus intended to indicate the correct flicker perception level for all practical voltage fluctuation waveforms. Information is presented to enable such an instrument to be constructed. A method is given for the evaluation of flicker severity on the basis of the output of flickermeters complying with this standard. The object of IEC 61000-4-15:2010 is to provide basic information for the design and the instrumentation of an analogue or digital flicker measuring apparatus. It does not give tolerance limit values of flicker severity.

Keywords: adoption, flicker, IEEE 1453, voltage fluctuation

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This introduction is not part of IEEE Std 1453-2011, IEEE Recommended Practice—Adoption of IEC 61000-4-15:2010, Electromagnetic compatibility (EMC)—Testing and measurement techniques—Flickermeter—Functional and design specifications.

Voltage fluctuations on electric power systems sometimes give rise to noticeable illumination changes from lighting equipment. The frequency of these voltage fluctuations is much less than the 50 Hz or 60 Hz supply frequency; however, they may occur with enough frequency and magnitude to cause irritation for people observing the illumination changes. This phenomenon is often referred to as flicker, lamp flicker, and sometimes voltage flicker. Often times, the terms have been used interchangeably. For many years, IEEE Std 141™-1993 and IEEE Std 519™-1992 have contained charts showing allowable voltage fluctuations. These charts in IEEE Std 141-1993 and IEEE Std 519-1992 show allowable voltage change magnitude on the vertical axis and frequency of occurrence on the horizontal axis. Although it is unclear, they appear to be based on 60 W, 120 V incandescent lamps subjected to rectangular voltage fluctuations. The advent of high-power electronic utilization equipment and mitigation equipment has given rise to some very complex voltage fluctuations that are not easily handled by IEEE Std 141-1993 and IEEE Std 519-1992. For this reason, the IEEE has worked in close cooperation with the International Union for Electroheat (UIE) and the International Electrotechnical Commission (IEC) to enhance existing standards to include a broader part of the world community.

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**Electromagnetic compatibility (EMC) –
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**Compatibilité électromagnétique (CEM) –
Partie 4-15: Techniques d'essai et de mesure – Flickermètre – Spécifications
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ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-15: Testing and measurement techniques – Flickermeter – Functional and design specifications

FOREWORD

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International Standard IEC 61000-4-15 has been prepared by subcommittee 77A: Low frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

IEC 61000-4-15 is based on work by the "Disturbances" Working Group of the International Union for Electroheat (UIE), on work of the IEEE, and on work within IEC itself.

It forms part 4-15 of the IEC 61000 series. It has the status of a basic EMC publication in accordance with IEC Guide 107.

This second edition cancels and replaces the first edition published in 1997 and its Amendment 1 (2003) and constitutes a technical revision. This new edition, in particular, adds or clarifies the definition of several directly measured parameters, so that diverging interpretations are avoided.

The text of this standard is based on the following documents:

FDIS	Report on voting
77A/722/FDIS	77A/730/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 61000 series, under the general title *Electromagnetic compatibility (EMC)* can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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- Part 1: General
 - General consideration (introduction, fundamental principles)
 - Definitions, terminology
- Part 2: Environment
 - Description of the environment
 - Classification of the environment
 - Compatibility levels
- Part 3: Limits
 - Emission limits
 - Immunity limits (in so far as they do not fall under the responsibility of the product committees)
- Part 4: Testing and measurement techniques
 - Measurement techniques
 - Testing techniques
- Part 5: Installation and mitigation guidelines
 - Installation guidelines
 - Mitigation methods and devices
- Part 6: Generic standards
- Part 9: Miscellaneous

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ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-15: Testing and measurement techniques – Flickermeter – Functional and design specifications

1 Scope and object

This part of IEC 61000 gives a functional and design specification for flicker measuring apparatus intended to indicate the correct flicker perception level for all practical voltage fluctuation waveforms. Information is presented to enable such an instrument to be constructed. A method is given for the evaluation of flicker severity on the basis of the output of flickermeters complying with this standard.

The flickermeter specifications in this part of IEC 61000 relate only to measurements of 120 V and 230 V, 50 Hz and 60 Hz inputs. Characteristics of some incandescent lamps for other voltages are sufficiently similar to the values in Table 1 and Table 2, that the use of a correction factor can be applied for those other voltages. Some of these correction factors are provided in the Annex B. Detailed specifications for voltages and frequencies other than those given above, remain under consideration.

The object of this part of IEC 61000 is to provide basic information for the design and the instrumentation of an analogue or digital flicker measuring apparatus. It does not give tolerance limit values of flicker severity.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068 (all parts), *Environmental testing*

IEC 61000-3-3, *Electromagnetic compatibility (EMC) – Part 3-3: Limits – Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current ≤ 16 A per phase and not subject to conditional connection*

IEC 61000-3-11, *Electromagnetic compatibility (EMC) – Part 3-11: Limits – Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems – Equipment with rated current ≤ 75 A and subject to conditional connection*

IEC 61010-1, *Safety requirements for electrical equipment for measurement, control, and laboratory use – Part 1: General requirements*

IEC 61326-1, *Electrical equipment for measurement, control and laboratory use – EMC requirements – Part 1: General requirements*